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Sheet 1 of 1

ATTORNEY DOCKET NO.	SERIAL NO.	
9319S-000656	To be assigned	
APPLICANT		
Osamu SHINKAWA		
FILING DATE	GROUP	
Herewith	To be assigned	

U.S. PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.						

FOREIGN PATENT DOCUMENTS								
Ref. Desig.	Examiner's Initials	Document Number	Date	Country		Class/ Subclass	Translation Yes	n* No
1.	JL	08-309963	11/26/1996	Japan			×	

OTHE	OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)						
Ref. Desig.	Examiner's Initials						
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Examiner: /Jannelle Lebron/ Date Considered: 05/11/2006

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ATTORNEY DOCKET No.	SERIAL NO.		
9319S-000656	10/789,940		
APPLICANT			
Osamu Shinkawa			
FILING DATE	GROUP		
February 27, 2004	2861		

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FOREIGN PATENT DOCUMENTS						
Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation * Yes No
1.	JĻ	63-141750	6/14/1988	Japan		Abstract
2.	JL	11-334102	12/7/1999	Japan		х
3.	JL	02-003323	1/8/1990	Japan ·		Abstract
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4.	JL	2000-272116	10/3/2000	Japan		×

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Sheet 1 of 1

SERIAL NO.	
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	10/789,940 GROUP

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2.	JL	6,375,299	4/23/2002	Foster et al			
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2.	JL	EP 1 147 900 A1	4/20/2000	Europe		N/A	
3.	JL	EP 0 933 215 A2	2/1/1999	Europe		N/A	

OTHE	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)					
Ref. Desig.	Examiner's Initials					
Desig.	JL	Communication from European Patent Office re: counterpart application				

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